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Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Active
Number of LABs/CLBs	162000
Number of Logic Elements/Cells	2835000
Total RAM Bits	396150400
Number of I/O	416
Number of Gates	-
Voltage - Supply	0.873V ~ 0.927V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 100°C (TJ)
Package / Case	2104-BBGA, FCBGA
Supplier Device Package	2104-FCBGA (47.5x47.5)
Purchase URL	https://www.e-xfl.com/product-detail/xilinx/xcvu11p-3flgc2104e

Table 2: Recommended Operating Conditions⁽¹⁾⁽²⁾ (Cont'd)

Symbol	Description	Min	Typ	Max	Units
SYSMON					
V _{CCADC}	SYSMON supply relative to GNDADC.	1.746	1.800	1.854	V
V _{REFP}	SYSMON externally supplied reference voltage relative to GNDADC.	1.200	1.250	1.300	V
Temperature					
T _j ⁽¹¹⁾	Junction temperature operating range for extended (E) temperature devices. ⁽¹²⁾	0	–	100	°C
	Junction temperature operating range for industrial (I) temperature devices.	–40	–	100	°C
	Junction temperature operating range for eFUSE programming. ⁽¹³⁾	–40	–	125	°C

Notes:

- All voltages are relative to GND.
- For the design of the power distribution system consult *UltraScale Architecture PCB Design Guide* ([UG583](#)).
- V_{CCINT_IO} must be connected to V_{CCBRAM}.
- For V_{CCO_0}, the minimum recommended operating voltage for power on and during configuration is 1.425V. After configuration, data is retained even if V_{CCO} drops to 0V.
- Includes V_{CCO} of 1.0V, 1.2V, 1.35V, 1.5V, and 1.8V.
- V_{CCAUX_IO} must be connected to V_{CCAUX}.
- The lower absolute voltage specification always applies.
- A total of 200 mA per bank should not be exceeded.
- If battery is not used, connect V_{BATT} to either GND or V_{CCAUX}.
- Each voltage listed requires filtering as described in the *UltraScale Architecture GTY Transceiver User Guide* ([UG578](#)).
- Xilinx recommends measuring the T_j of a device using the system monitor as described in the *UltraScale Architecture System Monitor User Guide* ([UG580](#)). The SYSMON temperature measurement errors (that are described in [Table 58](#)) must be accounted for in your design. For example, by using an external reference of 1.25V, when SYSMON reports 97°C, there is a measurement error ±3°C. A reading of 97°C is considered the maximum adjusted T_j (100°C – 3°C = 97°C).
- Devices labeled with the speed/temperature grade of -2LE can operate for a limited time at a junction temperature of 110°C. Timing parameters adhere to the same speed file at 110°C as they do below 110°C, regardless of operating voltage (nominal voltage of 0.85V or a low-voltage of 0.72V). Operation at T_j = 110°C is limited to 1% of the device lifetime and can occur sequentially or at regular intervals as long as the total time does not exceed 1% of the device lifetime.
- Do not program eFUSE during device configuration (e.g., during configuration, during configuration readback, or when readback CRC is active).

V_{IN} Maximum Allowed AC Voltage Overshoot and Undershoot

Table 4: V_{IN} Maximum Allowed AC Voltage Overshoot and Undershoot for HP I/O Banks⁽¹⁾⁽²⁾

AC Voltage Overshoot	% of UI at –40°C to 100°C	AC Voltage Undershoot	% of UI at –40°C to 100°C
V _{CCO} + 0.30	100%	–0.30	100%
V _{CCO} + 0.35	100%	–0.35	90%
V _{CCO} + 0.40	92%	–0.40	92%
V _{CCO} + 0.45	50%	–0.45	50%
V _{CCO} + 0.50	20%	–0.50	20%
V _{CCO} + 0.55	10%	–0.55	10%
V _{CCO} + 0.60	6%	–0.60	6%
V _{CCO} + 0.65	2%	–0.65	2%
V _{CCO} + 0.70	2%	–0.70	2%

Notes:

1. A total of 200 mA per bank should not be exceeded.
2. For UI smaller than 20 μs.

Quiescent Supply Current

Table 5: Typical Quiescent Supply Current⁽¹⁾⁽²⁾⁽³⁾

Symbol	Description	Device	Speed Grade and V _{CCINT} Operating Voltages				Units
			0.90V	0.85V		0.72V	
			-3	-2	-1	-2	
I _{CCINTQ}	Quiescent V _{CCINT} supply current.	XCVU3P	2384	2276	2276	2017	mA
		XCVU5P	4769	4552	4552	4034	mA
		XCVU7P	4769	4552	4552	4034	mA
		XCVU9P	7153	6828	6828	6050	mA
		XCVU11P	7567	7202	7202	6332	mA
		XCVU13P	10090	9602	9602	8442	mA
I _{CCINT_IOQ}	Quiescent current for V _{CCINT_IO} supply.	XCVU3P	149	144	144	144	mA
		XCVU5P	298	287	287	287	mA
		XCVU7P	298	287	287	287	mA
		XCVU9P	447	431	431	431	mA
		XCVU11P	182	176	176	176	mA
		XCVU13P	243	234	234	234	mA
I _{CCOQ}	Quiescent V _{CCO} supply current.	All devices	1	1	1	1	mA
I _{CCAUXQ}	Quiescent V _{CCAUX} supply current.	XCVU3P	268	268	268	268	mA
		XCVU5P	535	535	535	535	mA
		XCVU7P	535	535	535	535	mA
		XCVU9P	1015	1015	1015	1015	mA
		XCVU11P	819	819	819	819	mA
		XCVU13P	1091	1091	1091	1091	mA

Power Supply Requirements

Table 6 shows the minimum current, in addition to I_{CCQ} maximum, required by each Virtex UltraScale+ FPGA for proper power-on and configuration. If the current minimums shown in Table 6 are met, the device powers on after all supplies have passed through their power-on reset threshold voltages. The device must not be configured until after V_{CCINT} is applied. Once initialized and configured, use the Xilinx Power Estimator (XPE) tools to estimate current drain on these supplies.

Table 6: Power-on Current by Device⁽¹⁾

Device	$I_{CCINTMIN}$	$I_{CCINT_IOMIN} + I_{CCBRAMMIN}$	I_{CCOMIN}	$I_{CCAUXMIN} + I_{CCAUX_IOMIN}$	Units
XCVU3P	$I_{CCINTQ} + 2000$	$I_{CCBRAMQ} + I_{CCINT_IOQ} + 950$	$I_{CCOQ} + 50$	$I_{CCAUXQ} + I_{CCAUX_IOQ} + 350$	mA
XCVU5P	$I_{CCINTQ} + 4000$	$I_{CCBRAMQ} + I_{CCINT_IOQ} + 1900$	$I_{CCOQ} + 100$	$I_{CCAUXQ} + I_{CCAUX_IOQ} + 700$	mA
XCVU7P	$I_{CCINTQ} + 4000$	$I_{CCBRAMQ} + I_{CCINT_IOQ} + 1900$	$I_{CCOQ} + 100$	$I_{CCAUXQ} + I_{CCAUX_IOQ} + 700$	mA
XCVU9P	$I_{CCINTQ} + 6000$	$I_{CCBRAMQ} + I_{CCINT_IOQ} + 2850$	$I_{CCOQ} + 150$	$I_{CCAUXQ} + I_{CCAUX_IOQ} + 1050$	mA
XCVU11P	$I_{CCINTQ} + 6549$	$I_{CCBRAMQ} + I_{CCINT_IOQ} + 3111$	$I_{CCOQ} + 164$	$I_{CCAUXQ} + I_{CCAUX_IOQ} + 1146$	mA
XCVU13P	$I_{CCINTQ} + 8731$	$I_{CCBRAMQ} + I_{CCINT_IOQ} + 4148$	$I_{CCOQ} + 219$	$I_{CCAUXQ} + I_{CCAUX_IOQ} + 1528$	mA

Notes:

1. Use the Xilinx Power Estimator (XPE) spreadsheet tool (download at www.xilinx.com/power) to estimate power-on current for all supplies.

Table 7 shows the power supply ramp time.

Table 7: Power Supply Ramp Time

Symbol	Description	Min	Max	Units
T_{VCCINT}	Ramp time from GND to 95% of V_{CCINT} .	0.2	40	ms
T_{VCCINT_IO}	Ramp time from GND to 95% of V_{CCINT_IO} .	0.2	40	ms
T_{VCCO}	Ramp time from GND to 95% of V_{CCO} .	0.2	40	ms
T_{VCCAUX}	Ramp time from GND to 95% of V_{CCAUX} .	0.2	40	ms
$T_{VCCBRAM}$	Ramp time from GND to 95% of V_{CCBRAM} .	0.2	40	ms
$T_{MGTAVCC}$	Ramp time from GND to 95% of $V_{MGTAVCC}$.	0.2	40	ms
$T_{MGTAVTT}$	Ramp time from GND to 95% of $V_{MGTAVTT}$.	0.2	40	ms
$T_{MGTVCCAUX}$	Ramp time from GND to 95% of $V_{MGTVCCAUX}$.	0.2	40	ms

DC Input and Output Levels

Values for V_{IL} and V_{IH} are recommended input voltages. Values for I_{OL} and I_{OH} are guaranteed over the recommended operating conditions at the V_{OL} and V_{OH} test points. Only selected standards are tested. These are chosen to ensure that all standards meet their specifications. The selected standards are tested at a minimum V_{CCO} with the respective V_{OL} and V_{OH} voltage levels shown. Other standards are sample tested.

Table 8: SelectIO DC Input and Output Levels for the I/O Banks⁽¹⁾⁽²⁾⁽³⁾

I/O Standard	V_{IL}		V_{IH}		V_{OL}	V_{OH}	I_{OL}	I_{OH}
	V, Min	V, Max	V, Min	V, Max	V, Max	V, Min	mA	mA
HSTL_I	-0.300	$V_{REF} - 0.100$	$V_{REF} + 0.100$	$V_{CCO} + 0.300$	0.400	$V_{CCO} - 0.400$	5.8	-5.8
HSTL_I_12	-0.300	$V_{REF} - 0.080$	$V_{REF} + 0.080$	$V_{CCO} + 0.300$	25% V_{CCO}	75% V_{CCO}	4.1	-4.1
HSTL_I_18	-0.300	$V_{REF} - 0.100$	$V_{REF} + 0.100$	$V_{CCO} + 0.300$	0.400	$V_{CCO} - 0.400$	6.2	-6.2
HSUL_12	-0.300	$V_{REF} - 0.130$	$V_{REF} + 0.130$	$V_{CCO} + 0.300$	20% V_{CCO}	80% V_{CCO}	0.1	-0.1
LVC MOS12	-0.300	35% V_{CCO}	65% V_{CCO}	$V_{CCO} + 0.300$	0.400	$V_{CCO} - 0.400$	Note 4	Note 4
LVC MOS15	-0.300	35% V_{CCO}	65% V_{CCO}	$V_{CCO} + 0.300$	0.450	$V_{CCO} - 0.450$	Note 5	Note 5
LVC MOS18	-0.300	35% V_{CCO}	65% V_{CCO}	$V_{CCO} + 0.300$	0.450	$V_{CCO} - 0.450$	Note 5	Note 5
LVDCI_15	-0.300	35% V_{CCO}	65% V_{CCO}	$V_{CCO} + 0.300$	0.450	$V_{CCO} - 0.450$	7.0	-7.0
LVDCI_18	-0.300	35% V_{CCO}	65% V_{CCO}	$V_{CCO} + 0.300$	0.450	$V_{CCO} - 0.450$	7.0	-7.0
SSTL12	-0.300	$V_{REF} - 0.100$	$V_{REF} + 0.100$	$V_{CCO} + 0.300$	$V_{CCO}/2 - 0.150$	$V_{CCO}/2 + 0.150$	8.0	-8.0
SSTL135	-0.300	$V_{REF} - 0.090$	$V_{REF} + 0.090$	$V_{CCO} + 0.300$	$V_{CCO}/2 - 0.150$	$V_{CCO}/2 + 0.150$	9.0	-9.0
SSTL15	-0.300	$V_{REF} - 0.100$	$V_{REF} + 0.100$	$V_{CCO} + 0.300$	$V_{CCO}/2 - 0.175$	$V_{CCO}/2 + 0.175$	10.0	-10.0
SSTL18_I	-0.300	$V_{REF} - 0.125$	$V_{REF} + 0.125$	$V_{CCO} + 0.300$	$V_{CCO}/2 - 0.470$	$V_{CCO}/2 + 0.470$	7.0	-7.0
MIPI_DPHY_DCI_LP ⁽⁶⁾	-0.300	0.550	0.880	$V_{CCO} + 0.300$	0.050	1.100	0.01	-0.01

Notes:

1. Tested according to relevant specifications.
2. Standards specified using the default I/O standard configuration. For details, see the *UltraScale Architecture SelectIO Resources User Guide* ([UG571](#)).
3. POD10 and POD12 DC input and output levels are shown in [Table 9](#), [Table 13](#), and [Table 14](#).
4. Supported drive strengths of 2, 4, 6, or 8 mA in the I/O banks.
5. Supported drive strengths of 2, 4, 6, 8, or 12 mA in the I/O banks.
6. Low-power option for MIPI_DPHY_DCI.

Table 9: DC Input Levels for Single-ended POD10 and POD12 I/O Standards⁽¹⁾⁽²⁾

I/O Standard	V_{IL}		V_{IH}	
	V, Min	V, Max	V, Min	V, Max
POD10	-0.300	$V_{REF} - 0.068$	$V_{REF} + 0.068$	$V_{CCO} + 0.300$
POD12	-0.300	$V_{REF} - 0.068$	$V_{REF} + 0.068$	$V_{CCO} + 0.300$

Notes:

1. Tested according to relevant specifications.
2. Standards specified using the default I/O standard configuration. For details, see the *UltraScale Architecture SelectIO Resources User Guide* ([UG571](#)).

AC Switching Characteristics

All values represented in this data sheet are based on the speed specifications in the Vivado® Design Suite as outlined in [Table 16](#).

Table 16: Speed Specification Version By Device

2017.1	Device
1.10	XCVU3P, XCVU7P, XCVU9P, XCVU5P, XCVU11P, XCVU13P

Switching characteristics are specified on a per-speed-grade basis and can be designated as Advance, Preliminary, or Production. Each designation is defined as follows:

Advance Product Specification

These specifications are based on simulations only and are typically available soon after device design specifications are frozen. Although speed grades with this designation are considered relatively stable and conservative, some under-reporting might still occur.

Preliminary Product Specification

These specifications are based on complete ES (engineering sample) silicon characterization. Devices and speed grades with this designation are intended to give a better indication of the expected performance of production silicon. The probability of under-reporting delays is greatly reduced as compared to Advance data.

Product Specification

These specifications are released once enough production silicon of a particular device family member has been characterized to provide full correlation between specifications and devices over numerous production lots. There is no under-reporting of delays, and customers receive formal notification of any subsequent changes. Typically, the slowest speed grades transition to production before faster speed grades.

Testing of AC Switching Characteristics

Internal timing parameters are derived from measuring internal test patterns. All AC switching characteristics are representative of worst-case supply voltage and junction temperature conditions.

For more specific, more precise, and worst-case guaranteed data, use the values reported by the static timing analyzer and back-annotate to the simulation net list. Unless otherwise noted, values apply to all Virtex UltraScale+ FPGAs.

Production Silicon and Software Status

In some cases, a particular family member (and speed grade) is released to production before a speed specification is released with the correct label (Advance, Preliminary, Production). Any labeling discrepancies are corrected in subsequent speed specification releases.

Table 18 lists the production released Virtex UltraScale+ FPGA, speed grade, and the minimum corresponding supported speed specification version and Vivado software revisions. The Vivado software and speed specifications listed are the minimum releases required for production. All subsequent releases of software and speed specifications are valid.

Table 18: Virtex UltraScale+ FPGA Device Production Software and Speed Specification Release

Device	Speed Grade and V_{CCINT} Operating Voltages				
	0.90V	0.85V			0.72V
	-3	-2	-1	-2L	-2L
XCVU3P		Vivado tools 2017.1 v1.10			
XCVU5P					
XCVU7P					
XCVU9P					
XCVU11P					
XCVU13P					

Notes:

- Blank entries indicate a device and/or speed grade in Advance or Preliminary status.

FPGA Logic Performance Characteristics

This section provides the performance characteristics of some common functions and designs implemented in Virtex UltraScale+ FPGAs. These values are subject to the same guidelines as the [AC Switching Characteristics](#), page 13.

Table 19: LVDS Component Mode Performance

Description	Speed Grade and V _{CCINT} Operating Voltages								Units
	0.90V		0.85V				0.72V		
	-3		-2		-1		-2		
	Min	Max	Min	Max	Min	Max	Min	Max	
LVDS TX DDR (OSERDES 4:1, 8:1)	0	1250	0	1250	0	1250	0	1250	Mb/s
LVDS TX SDR (OSERDES 2:1, 4:1)	0	625	0	625	0	625	0	625	Mb/s
LVDS RX DDR (ISERDES 1:4, 1:8) ⁽¹⁾	0	1250	0	1250	0	1250	0	1250	Mb/s
LVDS RX SDR (ISERDES 1:2, 1:4) ⁽¹⁾	0	625	0	625	0	625	0	625	Mb/s

Notes:

1. LVDS receivers are typically bounded with certain applications to achieve maximum performance. Package skews are not included and should be removed through PCB routing.

Table 20: LVDS Native Mode Performance⁽¹⁾⁽²⁾

Description	DATA_WIDTH	Speed Grade and V _{CCINT} Operating Voltages								Units
		0.90V		0.85V				0.72V		
		-3		-2		-1		-2		
		Min	Max	Min	Max	Min	Max	Min	Max	
LVDS TX DDR (TX_BITSLICE)	4	375	1600	375	1600	375	1260	375	1400	Mb/s
	8	375	1600	375	1600	375	1260	375	1600	Mb/s
LVDS TX SDR (TX_BITSLICE)	4	187.5	800	187.5	800	187.5	630	187.5	700	Mb/s
	8	187.5	800	187.5	800	187.5	630	187.5	800	Mb/s
LVDS RX DDR (RX_BITSLICE) ⁽³⁾	4	375	1600	375	1600	375	1260	375	1400	Mb/s
	8	375	1600	375	1600	375	1260	375	1600	Mb/s
LVDS RX SDR (RX_BITSLICE) ⁽³⁾	4	187.5	800	187.5	800	187.5	630	187.5	700	Mb/s
	8	187.5	800	187.5	800	187.5	630	187.5	800	Mb/s

Notes:

1. Native mode is supported through the [High-Speed SelectIO Interface Wizard](#) available with the Vivado Design Suite.
2. PLL settings can restrict the minimum allowable data rate. For example, when using the PLL with CLKOUTPHY_MODE = VCO_HALF the minimum frequency is PLL_FVCOMIN/2.
3. LVDS receivers are typically bounded with certain applications to achieve maximum performance. Package skews are not included and should be removed through PCB routing.

Table 21: MIPI D-PHY Performance

Description	Speed Grade and V _{CCINT} Operating Voltages				Units
	0.90V	0.85V		0.72V	
	-3	-2	-1	-2	
MIPI D-PHY transmitter or receiver.	1500	1500	1260	1260	Mb/s

Table 24: IOB High Performance (HP) Switching Characteristics (Cont'd)

I/O Standards	T _{INBUF_DELAY_PAD_I}				T _{OUTBUF_DELAY_O_PAD}				T _{OUTBUF_DELAY_TD_PAD}				Units
	0.90V	0.85V		0.72V	0.90V	0.85V		0.72V	0.90V	0.85V		0.72V	
	-3	-2	-1	-2	-3	-2	-1	-2	-3	-2	-1	-2	
HSLVDCI_18_S	0.424	0.424	0.447	0.424	0.761	0.761	0.817	0.761	0.836	0.836	0.900	0.836	ns
HSTL_I_12_F	0.378	0.378	0.399	0.378	0.423	0.423	0.443	0.423	0.553	0.553	0.582	0.553	ns
HSTL_I_12_M	0.378	0.378	0.399	0.378	0.551	0.551	0.582	0.551	0.642	0.642	0.679	0.642	ns
HSTL_I_12_S	0.378	0.378	0.399	0.378	0.750	0.750	0.799	0.750	0.813	0.813	0.868	0.813	ns
HSTL_I_18_F	0.322	0.322	0.339	0.322	0.456	0.456	0.474	0.456	0.576	0.576	0.606	0.576	ns
HSTL_I_18_M	0.322	0.322	0.339	0.322	0.569	0.569	0.602	0.569	0.653	0.653	0.692	0.653	ns
HSTL_I_18_S	0.322	0.322	0.339	0.322	0.781	0.781	0.833	0.781	0.816	0.816	0.871	0.816	ns
HSTL_I_DCI_12_F	0.378	0.378	0.399	0.378	0.406	0.406	0.429	0.406	0.534	0.534	0.564	0.534	ns
HSTL_I_DCI_12_M	0.378	0.378	0.399	0.378	0.556	0.556	0.586	0.556	0.654	0.654	0.694	0.654	ns
HSTL_I_DCI_12_S	0.378	0.378	0.399	0.378	0.754	0.754	0.803	0.754	0.842	0.842	0.907	0.842	ns
HSTL_I_DCI_18_F	0.321	0.321	0.339	0.321	0.445	0.445	0.461	0.445	0.566	0.566	0.595	0.566	ns
HSTL_I_DCI_18_M	0.321	0.321	0.339	0.321	0.554	0.554	0.585	0.554	0.643	0.643	0.684	0.643	ns
HSTL_I_DCI_18_S	0.321	0.321	0.339	0.321	0.761	0.761	0.817	0.761	0.836	0.836	0.900	0.836	ns
HSTL_I_DCI_F	0.393	0.393	0.415	0.393	0.431	0.431	0.445	0.431	0.555	0.555	0.575	0.555	ns
HSTL_I_DCI_M	0.393	0.393	0.415	0.393	0.552	0.552	0.581	0.552	0.644	0.644	0.684	0.644	ns
HSTL_I_DCI_S	0.393	0.393	0.415	0.393	0.766	0.766	0.821	0.766	0.847	0.847	0.912	0.847	ns
HSTL_I_F	0.378	0.378	0.399	0.378	0.423	0.423	0.443	0.423	0.549	0.549	0.581	0.549	ns
HSTL_I_M	0.378	0.378	0.399	0.378	0.554	0.554	0.585	0.554	0.640	0.640	0.677	0.640	ns
HSTL_I_S	0.378	0.378	0.399	0.378	0.766	0.766	0.816	0.766	0.811	0.811	0.866	0.811	ns
HSUL_12_DCI_F	0.378	0.378	0.399	0.378	0.425	0.425	0.443	0.425	0.558	0.558	0.586	0.558	ns
HSUL_12_DCI_M	0.378	0.378	0.399	0.378	0.556	0.556	0.586	0.556	0.654	0.654	0.694	0.654	ns
HSUL_12_DCI_S	0.378	0.378	0.399	0.378	0.736	0.736	0.784	0.736	0.821	0.821	0.886	0.821	ns
HSUL_12_F	0.378	0.378	0.399	0.378	0.412	0.412	0.430	0.412	0.538	0.538	0.566	0.538	ns
HSUL_12_M	0.378	0.378	0.399	0.378	0.551	0.551	0.582	0.551	0.642	0.642	0.679	0.642	ns
HSUL_12_S	0.378	0.378	0.399	0.378	0.750	0.750	0.799	0.750	0.813	0.813	0.868	0.813	ns
LVC MOS12_F_2	0.512	0.512	0.555	0.512	0.672	0.672	0.692	0.672	0.898	0.898	0.922	0.898	ns
LVC MOS12_F_4	0.512	0.512	0.555	0.512	0.504	0.504	0.521	0.504	0.664	0.664	0.693	0.664	ns
LVC MOS12_F_6	0.512	0.512	0.555	0.512	0.485	0.485	0.507	0.485	0.634	0.634	0.669	0.634	ns
LVC MOS12_F_8	0.512	0.512	0.555	0.512	0.465	0.465	0.489	0.465	0.611	0.611	0.666	0.611	ns
LVC MOS12_M_2	0.512	0.512	0.555	0.512	0.708	0.708	0.727	0.708	0.916	0.916	0.945	0.916	ns
LVC MOS12_M_4	0.512	0.512	0.555	0.512	0.550	0.550	0.573	0.550	0.664	0.664	0.690	0.664	ns
LVC MOS12_M_6	0.512	0.512	0.555	0.512	0.527	0.527	0.554	0.527	0.622	0.622	0.652	0.622	ns
LVC MOS12_M_8	0.512	0.512	0.555	0.512	0.540	0.540	0.571	0.540	0.614	0.614	0.649	0.614	ns
LVC MOS12_S_2	0.512	0.512	0.555	0.512	0.767	0.767	0.803	0.767	0.990	0.990	1.024	0.990	ns
LVC MOS12_S_4	0.512	0.512	0.555	0.512	0.666	0.666	0.704	0.666	0.803	0.803	0.848	0.803	ns
LVC MOS12_S_6	0.512	0.512	0.555	0.512	0.657	0.657	0.695	0.657	0.732	0.732	0.774	0.732	ns
LVC MOS12_S_8	0.512	0.512	0.555	0.512	0.708	0.708	0.761	0.708	0.745	0.745	0.790	0.745	ns
LVC MOS15_F_12	0.414	0.414	0.445	0.414	0.500	0.500	0.522	0.500	0.647	0.647	0.682	0.647	ns
LVC MOS15_F_2	0.414	0.414	0.445	0.414	0.702	0.702	0.722	0.702	0.919	0.919	0.940	0.919	ns
LVC MOS15_F_4	0.414	0.414	0.445	0.414	0.579	0.579	0.601	0.579	0.755	0.755	0.781	0.755	ns
LVC MOS15_F_6	0.414	0.414	0.445	0.414	0.547	0.547	0.569	0.547	0.711	0.711	0.742	0.711	ns

Table 26: Input Delay Measurement Methodology (Cont'd)

Description	I/O Standard Attribute	$V_L^{(1)(2)}$	$V_H^{(1)(2)}$	$V_{MEAS}^{(1)(4)(6)}$	$V_{REF}^{(1)(3)(5)}$
DIFF_HSUL, 1.2V	DIFF_HSUL_12	0.6 – 0.25	0.6 + 0.25	0 ⁽⁶⁾	–
DIFF_SSTL, 1.2V	DIFF_SSTL12	0.6 – 0.25	0.6 + 0.25	0 ⁽⁶⁾	–
DIFF_SSTL135 and DIFF_SSTL135 class II, 1.35V	DIFF_SSTL135, DIFF_SSTL135_II	0.675 – 0.2875	0.675 + 0.2875	0 ⁽⁶⁾	–
DIFF_SSTL15 and DIFF_SSTL15 class II, 1.5V	DIFF_SSTL15, DIFF_SSTL15_II	0.75 – 0.325	0.75 + 0.325	0 ⁽⁶⁾	–
DIFF_SSTL18_I, DIFF_SSTL18_II, 1.8V	DIFF_SSTL18_I, DIFF_SSTL18_II	0.9 – 0.4	0.9 + 0.4	0 ⁽⁶⁾	–
DIFF_POD10, 1.0V	DIFF_POD10	0.5 – 0.2	0.5 + 0.2	0 ⁽⁶⁾	–
DIFF_POD12, 1.2V	DIFF_POD12	0.6 – 0.25	0.6 + 0.25	0 ⁽⁶⁾	–
LVDS (low-voltage differential signaling), 1.8V	LVDS	0.9 – 0.125	0.9 + 0.125	0 ⁽⁶⁾	–
SUB_LVDS, 1.8V	SUB_LVDS	0.9 – 0.125	0.9 + 0.125	0 ⁽⁶⁾	–
SLVS, 1.8V	SLVS_400_18	0.9 – 0.125	0.9 + 0.125	0 ⁽⁶⁾	–
MIPI D-PHY (high speed) 1.2V	MIPI_DPHY_DCI_HS	0.2 – 0.125	0.2 + 0.125	0 ⁽⁶⁾	–
MIPI D-PHY (low power) 1.2V	MIPI_DPHY_DCI_LP	0.715 – 0.2	0.715 + 0.2	0 ⁽⁶⁾	–

Notes:

1. The input delay measurement methodology parameters for LVDCI/HSLVDCI are the same for LVCMOS standards of the same voltage. Parameters for all other DCI standards are the same for the corresponding non-DCI standards.
2. Input waveform switches between V_L and V_H .
3. Measurements are made at typical, minimum, and maximum V_{REF} values. Reported delays reflect worst case of these measurements. V_{REF} values listed are typical.
4. Input voltage level from which measurement starts.
5. This is an input voltage reference that bears no relation to the V_{REF}/V_{MEAS} parameters found in IBIS models and/or noted in Figure 1.
6. The value given is the differential input voltage.

Output Delay Measurement Methodology

Output delays are measured with short output traces. Standard termination was used for all testing. The propagation delay of the trace is characterized separately and subtracted from the final measurement, and is therefore not included in the generalized test setups shown in [Figure 1](#) and [Figure 2](#).

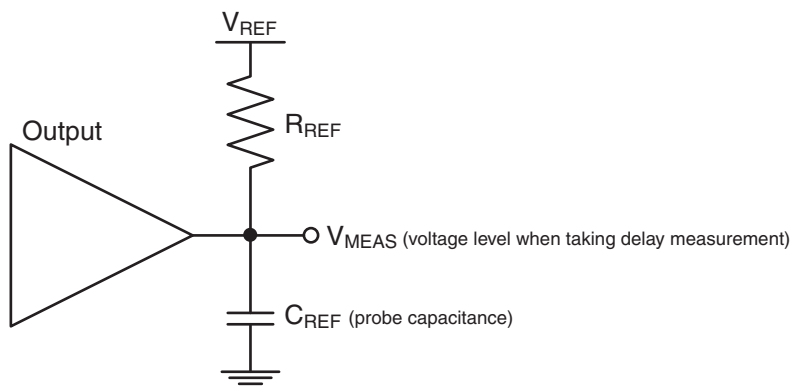


Figure 1: Single-Ended Test Setup

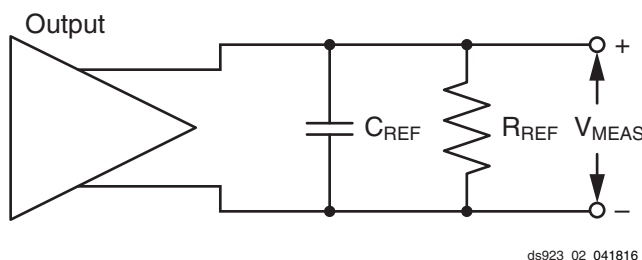


Figure 2: Differential Test Setup

Parameters V_{REF} , R_{REF} , C_{REF} , and V_{MEAS} fully describe the test conditions for each I/O standard. The most accurate prediction of propagation delay in any given application can be obtained through IBIS simulation, using this method:

1. Simulate the output driver of choice into the generalized test setup using values from [Table 27](#).
2. Record the time to V_{MEAS} .
3. Simulate the output driver of choice into the actual PCB trace and load using the appropriate IBIS model or capacitance value to represent the load.
4. Record the time to V_{MEAS} .
5. Compare the results of [step 2](#) and [step 4](#). The increase or decrease in delay yields the actual propagation delay of the PCB trace.

Table 27: Output Delay Measurement Methodology

Description	I/O Standard Attribute	R _{REF} (Ω)	C _{REF} ⁽¹⁾ (pF)	V _{MEAS} (V)	V _{REF} (V)
LVC MOS, 1.2V	LVC MOS12	1M	0	0.6	0
LVC MOS, 1.5V	LVC MOS15	1M	0	0.75	0
LVC MOS, 1.8V	LVC MOS18	1M	0	0.9	0
LVDCI, HSLVDCI, 1.5V	LVDCI_15, HSLVDCI_15	50	0	V _{REF}	0.75
LVDCI, HSLVDCI, 1.8V	LVDCI_15, HSLVDCI_18	50	0	V _{REF}	0.9
HSTL (high-speed transceiver logic), class I, 1.2V	HSTL_I_12	50	0	V _{REF}	0.6
HSTL, class I, 1.5V	HSTL_I	50	0	V _{REF}	0.75
HSTL, class I, 1.8V	HSTL_I_18	50	0	V _{REF}	0.9
HSUL (high-speed unterminated logic), 1.2V	HSUL_12	50	0	V _{REF}	0.6
SSTL12 (stub series terminated logic), 1.2V	SSTL12	50	0	V _{REF}	0.6
SSTL135, 1.35V	SSTL135	50	0	V _{REF}	0.675
SSTL15, 1.5V	SSTL15	50	0	V _{REF}	0.75
SSTL18, class I, 1.8V	SSTL18_I	50	0	V _{REF}	0.9
POD10, 1.0V	POD10	50	0	V _{REF}	1.0
POD12, 1.2V	POD12	50	0	V _{REF}	1.2
DIFF_HSTL, class I, 1.2V	DIFF_HSTL_I_12	50	0	V _{REF}	0.6
DIFF_HSTL, class I, 1.5V	DIFF_HSTL_I	50	0	V _{REF}	0.75
DIFF_HSTL, class I, 1.8V	DIFF_HSTL_I_18	50	0	V _{REF}	0.9
DIFF_HSUL, 1.2V	DIFF_HSUL_12	50	0	V _{REF}	0.6
DIFF_SSTL12, 1.2V	DIFF_SSTL12	50	0	V _{REF}	0.6
DIFF_SSTL135, 1.35V	DIFF_SSTL135	50	0	V _{REF}	0.675
DIFF_SSTL15, 1.5V	DIFF_SSTL15	50	0	V _{REF}	0.75
DIFF_SSTL18, 1.8V	DIFF_SSTL18_I	50	0	V _{REF}	0.9
DIFF_POD10, 1.0V	DIFF_POD10	50	0	V _{REF}	1.0
DIFF_POD12, 1.2V	DIFF_POD12	50	0	V _{REF}	1.2
LVDS (low-voltage differential signaling), 1.8V	LVDS	100	0	0 ⁽²⁾	0
SUB_LVDS, 1.8V	SUB_LVDS	100	0	0 ⁽²⁾	0
MIPI D-PHY (high speed) 1.2V	MIPI_DPHY_DCI_HS	100	0	0 ⁽²⁾	0
MIPI D-PHY (low power) 1.2V	MIPI_DPHY_DCI_LP	1M	0	0.6	0

Notes:

1. C_{REF} is the capacitance of the probe, nominally 0 pF.
2. The value given is the differential output voltage.

Block RAM and FIFO Switching Characteristics

Table 28: Block RAM and FIFO Switching Characteristics

Symbol	Description	Speed Grade and V _{CCINT} Operating Voltages				Units
		0.90V	0.85V		0.72V	
		-3	-2	-1	-2	
Maximum Frequency						
F _{MAX_WF_NC}	Block RAM (WRITE_FIRST and NO_CHANGE modes).	825	737	645	585	MHz
F _{MAX_RF}	Block RAM (READ_FIRST mode).	718	637	575	510	MHz
F _{MAX_FIFO}	FIFO in all modes without ECC.	825	737	645	585	MHz
F _{MAX_ECC}	Block RAM and FIFO in ECC configuration without PIPELINE.	718	637	575	510	MHz
	Block RAM and FIFO in ECC configuration with PIPELINE and Block RAM in WRITE_FIRST or NO_CHANGE mode.	825	737	645	585	MHz
T _{PW} ⁽¹⁾	Minimum pulse width.	495	542	543	577	ps
Block RAM and FIFO Clock-to-Out Delays						
T _{RCKO_DO}	Clock CLK to DOUT output (without output register).	0.91	1.02	1.11	1.46	ns, Max
T _{RCKO_DO_REG}	Clock CLK to DOUT output (with output register).	0.27	0.29	0.30	0.42	ns, Max

Notes:

1. The MMCM and PLL DUTY_CYCLE attribute should be set to 50% to meet the pulse-width requirements at the higher frequencies.

UltraRAM Switching Characteristics

Table 29: UltraRAM Switching Characteristics

Symbol	Description	Speed Grade and V _{CCINT} Operating Voltages				Units
		0.90V	0.85V		0.72V	
		-3	-2	-1	-2	
Maximum Frequency						
F _{MAX}	UltraRAM maximum frequency with OREG_B = True.	650	600	575	500	MHz
F _{MAX_ECC}	UltraRAM maximum frequency OREG_B = False and EN_ECC_RD_B = True.	450	400	386	325	MHz
F _{MAX_NORPIPELINE}	UltraRAM maximum frequency with OREG_B = False and EN_ECC_RD_B = False.	550	500	478	425	MHz
T _{PW} ⁽¹⁾	Minimum pulse width.	650	700	730	800	ps
T _{RSTPW}	Asynchronous reset minimum pulse width. One cycle required.	1 clock cycle				ps

Notes:

1. The MMCM and PLL DUTY_CYCLE attribute should be set to 50% to meet the pulse-width requirements at the higher frequencies.

Input/Output Delay Switching Characteristics

Table 30: Input/Output Delay Switching Characteristics

Symbol	Description	Speed Grade and V _{CCINT} Operating Voltages				Units
		0.90V	0.85V		0.72V	
		-3	-2	-1	-2	
F _{REFCLK}	REFCLK frequency for IDELAYCTRL (component mode).	300 to 800				MHz
	REFCLK frequency for BITSlice_CONTROL (native mode). ⁽¹⁾	300 to 2666.67	300 to 2666.67	300 to 2400	300 to 2400	MHz
T _{MINPER_CLK}	Minimum period for IDELAY clock.	3.195	3.195	3.195	3.195	ns
T _{MINPER_RST}	Minimum reset pulse width.	52.00				ns
T _{IDELAY_RESOLUTION} / T _{ODELAY_RESOLUTION}	IDELAY/ODELAY chain resolution.	2.1 to 12				ps

Notes:

1. PLL settings could restrict the minimum allowable data rate. For example, when using a PLL with CLKOUTPHY_MODE = VCO_HALF, the minimum frequency is PLL_FVCOMIN/2.

DSP48 Slice Switching Characteristics

Table 31: DSP48 Slice Switching Characteristics

Symbol	Description	Speed Grade and V _{CCINT} Operating Voltages				Units
		0.90V	0.85V		0.72V	
		-3	-2	-1	-2	
Maximum Frequency						
F _{MAX}	With all registers used.	891	775	645	644	MHz
F _{MAX_PATDET}	With pattern detector.	794	687	571	562	MHz
F _{MAX_MULT_NOMREG}	Two register multiply without MREG.	635	544	456	440	MHz
F _{MAX_MULT_NOMREG_PATDET}	Two register multiply without MREG with pattern detect.	577	492	410	395	MHz
F _{MAX_PREADD_NOADREG}	Without ADREG.	655	565	468	453	MHz
F _{MAX_NOPIPELINEREG}	Without pipeline registers (MREG, ADREG).	483	410	338	323	MHz
F _{MAX_NOPIPELINEREG_PATDET}	Without pipeline registers (MREG, ADREG) with pattern detect.	448	379	314	299	MHz

MMCM Switching Characteristics

Table 33: MMCM Specification

Symbol	Description	Speed Grade and V _{CCINT} Operating Voltages				Units
		0.90V	0.85V		0.72V	
		-3	-2	-1	-2	
MMCM_F _{INMAX}	Maximum input clock frequency.	1066	933	800	933	MHz
MMCM_F _{INMIN}	Minimum input clock frequency.	10	10	10	10	MHz
MMCM_F _{INJITTER}	Maximum input clock period jitter.	< 20% of clock input period or 1 ns Max				
MMCM_F _{INDUTY}	Input duty cycle range: 10–49 MHz.	25–75				%
	Input duty cycle range: 50–199 MHz.	30–70				%
	Input duty cycle range: 200–399 MHz.	35–65				%
	Input duty cycle range: 400–499 MHz.	40–60				%
	Input duty cycle range: >500 MHz.	45–55				%
MMCM_F _{MIN_PSCLK}	Minimum dynamic phase shift clock frequency.	0.01	0.01	0.01	0.01	MHz
MMCM_F _{MAX_PSCLK}	Maximum dynamic phase shift clock frequency.	550	500	450	500	MHz
MMCM_F _{VCOMIN}	Minimum MMCM VCO frequency.	800	800	800	800	MHz
MMCM_F _{VCOMAX}	Maximum MMCM VCO frequency.	1600	1600	1600	1600	MHz
MMCM_F _{BANDWIDTH}	Low MMCM bandwidth at typical. ⁽¹⁾	1.00	1.00	1.00	1.00	MHz
	High MMCM bandwidth at typical. ⁽¹⁾	4.00	4.00	4.00	4.00	MHz
MMCM_T _{STATPHAOFFSET}	Static phase offset of the MMCM outputs. ⁽²⁾	0.12	0.12	0.12	0.12	ns
MMCM_T _{OUTJITTER}	MMCM output jitter.	Note 3				
MMCM_T _{OUTDUTY}	MMCM output clock duty cycle precision. ⁽⁴⁾	0.165	0.20	0.20	0.20	ns
MMCM_T _{LOCKMAX}	MMCM maximum lock time for MMCM_F _{PFDMIN} .	100	100	100	100	μs
MMCM_F _{OUTMAX}	MMCM maximum output frequency.	891	775	667	725	MHz
MMCM_F _{OUTMIN}	MMCM minimum output frequency. ⁽⁴⁾⁽⁵⁾	6.25	6.25	6.25	6.25	MHz
MMCM_T _{EXTFDVAR}	External clock feedback variation.	< 20% of clock input period or 1 ns Max				
MMCM_RST _{MINPULSE}	Minimum reset pulse width.	5.00	5.00	5.00	5.00	ns
MMCM_F _{PFDMAX}	Maximum frequency at the phase frequency detector.	550	500	450	500	MHz
MMCM_F _{PFDMIN}	Minimum frequency at the phase frequency detector.	10	10	10	10	MHz
MMCM_T _{FBDELAY}	Maximum delay in the feedback path.	5 ns Max or one clock cycle				
MMCM_F _{DRPCLK_MAX}	Maximum DRP clock frequency	250	250	250	250	MHz

Notes:

1. The MMCM does not filter typical spread-spectrum input clocks because they are usually far below the bandwidth filter frequencies.
2. The static offset is measured between any MMCM outputs with identical phase.
3. Values for this parameter are available in the Clocking Wizard.
4. Includes global clock buffer.
5. Calculated as F_{VCO}/128 assuming output duty cycle is 50%.

Device Pin-to-Pin Input Parameter Guidelines

The pin-to-pin numbers in Table 38 are based on the clock root placement in the center of the device. The actual pin-to-pin values will vary if the root placement selected is different. Consult the Vivado Design Suite timing report for the actual pin-to-pin values.

Table 38: Global Clock Input Setup and Hold With MMCM

Symbol	Description	Device	Speed Grade and V _{CCINT} Operating Voltages				Units	
			0.90V	0.85V		0.72V		
			-3	-2	-1	-2		
Input Setup and Hold Time Relative to Global Clock Input Signal using SSTL15 Standard.(1)(2)(3)								
T _{PSMMCMCC_VU3P}	Global clock input and input flip-flop (or latch) with MMCM.	Setup	XCVU3P	1.86	1.86	1.99	2.32	ns
T _{PHMMCMCC_VU3P}		Hold	XCVU3P	−0.13	−0.13	−0.13	0.14	ns
T _{PSMMCMCC_VU5P}		Setup	XCVU5P	1.86	1.86	1.99	2.32	ns
T _{PHMMCMCC_VU5P}		Hold	XCVU5P	−0.13	−0.13	−0.13	0.14	ns
T _{PSMMCMCC_VU7P}		Setup	XCVU7P	1.86	1.86	1.99	2.32	ns
T _{PHMMCMCC_VU7P}		Hold	XCVU7P	−0.13	−0.13	−0.13	0.14	ns
T _{PSMMCMCC_VU9P}		Setup	XCVU9P	1.86	1.86	1.99	2.32	ns
T _{PHMMCMCC_VU9P}		Hold	XCVU9P	−0.13	−0.13	−0.13	0.14	ns
T _{PSMMCMCC_VU11P}		Setup	XCVU11P	1.92	1.92	2.05	2.36	ns
T _{PHMMCMCC_VU11P}		Hold	XCVU11P	−0.13	−0.13	−0.13	0.16	ns
T _{PSMMCMCC_VU13P}		Setup	XCVU13P	1.92	1.92	2.05	2.36	ns
T _{PHMMCMCC_VU13P}		Hold	XCVU13P	−0.13	−0.13	−0.13	0.16	ns

Notes:

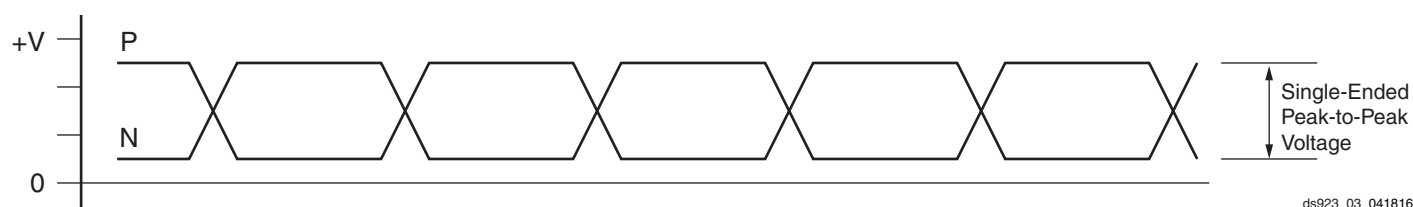
- Setup and hold times are measured over worst case conditions (process, voltage, temperature). Setup time is measured relative to the global clock input signal using the slowest process, slowest temperature, and slowest voltage. Hold time is measured relative to the global clock input signal using the fastest process, fastest temperature, and fastest voltage.
- This table lists representative values where one global clock input drives one vertical clock line in each accessible column, and where all accessible I/O and CLB flip-flops are clocked by the global clock net in a single SLR.
- Use IBIS to determine any duty-cycle distortion incurred using various standards.

Table 39: Sampling Window

Description	Speed Grade and V_{CCINT} Operating Voltages				Units
	0.90V	0.85V		0.72V	
	-3	-2	-1	-2	
$T_{SAMP_BUFG}^{(1)}$	510	610	610	610	ps
$T_{SAMP_NATIVE_DPA}$	100	100	125	125	ps
$T_{SAMP_NATIVE_BISC}$	60	60	85	85	ps

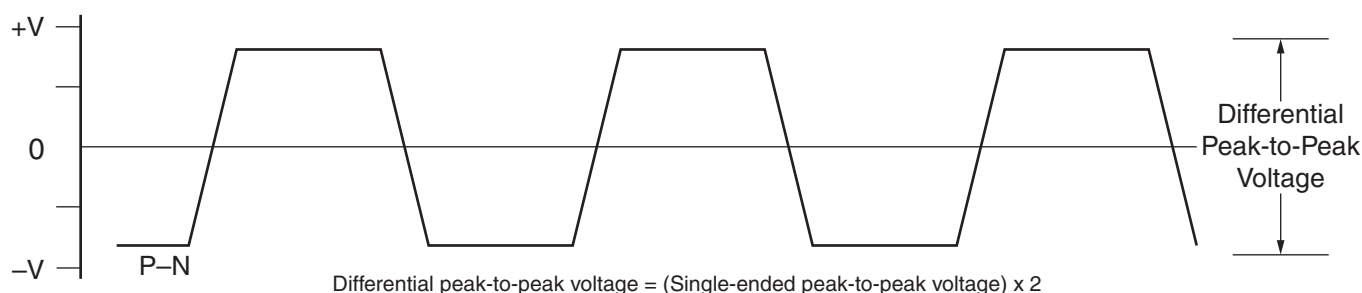
Notes:

- This parameter indicates the total sampling error of the Virtex UltraScale+ FPGA DDR input registers, measured across voltage, temperature, and process. The characterization methodology uses the MMCM to capture the DDR input registers' edges of operation. These measurements include: CLK0 MMCM jitter, MMCM accuracy (phase offset), and MMCM phase shift resolution. These measurements do not include package or clock tree skew.



ds923_03_041816

Figure 3: Single-Ended Peak-to-Peak Voltage



ds923_04_041816

Figure 4: Differential Peak-to-Peak Voltage

Table 42 and Table 43 summarize the DC specifications of the clock input of the GTY transceivers in Virtex UltraScale+ FPGAs. Consult www.xilinx.com/products/technology/high-speed-serial for further details.

Table 42: GTY Transceiver Clock DC Input Level Specification

Symbol	DC Parameter	Min	Typ	Max	Units
V_{IDIFF}	Differential peak-to-peak input voltage	250	–	2000	mV
R_{IN}	Differential input resistance	–	100	–	Ω
C_{EXT}	Required external AC coupling capacitor	–	10	–	nF

Table 43: GTY Transceiver Clock Output Level Specification

Symbol	Description	Conditions	Min	Typ	Max	Units
V_{OL}	Output high voltage for P and N	$R_T = 100\Omega$ across P and N signals	100	–	330	mV
V_{OH}	Output low voltage for P and N	$R_T = 100\Omega$ across P and N signals	500	–	700	mV
V_{DDOUT}	Differential output voltage (P–N), P = High (N–P), N = High	$R_T = 100\Omega$ across P and N signals	300	–	430	mV
V_{CMOUT}	Common mode voltage	$R_T = 100\Omega$ across P and N signals	300	–	500	mV

Table 48: GTY Transceiver PLL /Lock Time Adaptation

Symbol	Description	Conditions	All Speed Grades			Units
			Min	Typ	Max	
T _{LOCK}	Initial PLL lock.		–	–	1	ms
T _{DLOCK}	Clock recovery phase acquisition and adaptation time for decision feedback equalizer (DFE).	After the PLL is locked to the reference clock, this is the time it takes to lock the clock data recovery (CDR) to the data present at the input.	–	50,000	37 x 10 ⁶	UI
	Clock recovery phase acquisition and adaptation time for low-power mode (LPM) when the DFE is disabled.		–	50,000	2.3 x 10 ⁶	UI

Table 49: GTY Transceiver User Clock Switching Characteristics⁽¹⁾

Symbol	Description	Data Width Conditions (Bit)		Speed Grade and V _{CCINT} Operating Voltages				Units
				0.90V	0.85V		0.72V	
		Internal Logic	Interconnect Logic	-3	-2	-1	-2	
F _{TXOUTPMA}	TXOUTCLK maximum frequency sourced from OUTCLKPMA			511.719	511.719	402.833	402.833	MHz
F _{RXOUTPMA}	RXOUTCLK maximum frequency sourced from OUTCLKPMA			511.719	511.719	402.833	402.833	MHz
F _{TXOUTPROGDIV}	TXOUTCLK maximum frequency sourced from TXPROGDIVCLK			511.719	511.719	511.719	511.719	MHz
F _{RXOUTPROGDIV}	RXOUTCLK maximum frequency sourced from RXPROGDIVCLK			511.719	511.719	511.719	511.719	MHz
F _{TXIN}	TXUSRCLK ⁽²⁾ maximum frequency	16	16, 32	511.719	511.719	390.625	390.625	MHz
		32	32, 64	511.719	511.719	390.625	390.625	MHz
		64	64, 128	511.719	440.781	402.832	402.832	MHz
		20	20, 40	409.375	409.375	312.500	312.500	MHz
		40	40, 80	409.375	409.375	312.500	350.000	MHz
		80	80, 160	409.375	352.625	322.266	352.625	MHz
F _{RXIN}	RXUSRCLK ⁽²⁾ maximum frequency	16	16, 32	511.719	511.719	390.625	390.625	MHz
		32	32, 64	511.719	511.719	390.625	390.625	MHz
		64	64, 128	511.719	440.781	402.832	402.832	MHz
		20	20, 40	409.375	409.375	312.500	312.500	MHz
		40	40, 80	409.375	409.375	312.500	350.000	MHz
		80	80, 160	409.375	352.625	322.266	352.625	MHz

Table 51: GTY Transceiver Receiver Switching Characteristics

Symbol	Description	Condition	Min	Typ	Max	Units	
F _{GTYRX}	Serial data rate		0.500	–	F _{GTYMAX}	Gb/s	
R _{XSSST}	Receiver spread-spectrum tracking ⁽¹⁾		Modulated at 33 kHz	–5000	–	0	ppm
R _{XRL}	Run length (CID)			–	–	256	UI
R _{XPPMTOL}	Data/REFCLK PPM offset tolerance	Bit rates ≤ 6.6 Gb/s	–1250	–	1250	ppm	
		Bit rates > 6.6 Gb/s and ≤ 8.0 Gb/s	–700	–	700	ppm	
		Bit rates > 8.0 Gb/s	–200	–	200	ppm	
SJ Jitter Tolerance ⁽²⁾							
J _{T_SJ32.75}	Sinusoidal jitter (QPLL) ⁽³⁾	32.75 Gb/s	0.25	–	–	UI	
J _{T_SJ28.21}	Sinusoidal jitter (QPLL) ⁽³⁾	28.21 Gb/s	0.30	–	–	UI	
J _{T_SJ16.375}	Sinusoidal jitter (QPLL) ⁽³⁾	16.375 Gb/s	0.30	–	–	UI	
J _{T_SJ15.0}	Sinusoidal jitter (QPLL) ⁽³⁾	15.0 Gb/s	0.30	–	–	UI	
J _{T_SJ14.1}	Sinusoidal jitter (QPLL) ⁽³⁾	14.1 Gb/s	0.30	–	–	UI	
J _{T_SJ13.1}	Sinusoidal jitter (QPLL) ⁽³⁾	13.1 Gb/s	0.30	–	–	UI	
J _{T_SJ12.5}	Sinusoidal jitter (QPLL) ⁽³⁾	12.5 Gb/s	0.30	–	–	UI	
J _{T_SJ11.3}	Sinusoidal jitter (QPLL) ⁽³⁾	11.3 Gb/s	0.30	–	–	UI	
J _{T_SJ10.32_QPLL}	Sinusoidal jitter (QPLL) ⁽³⁾	10.32 Gb/s	0.30	–	–	UI	
J _{T_SJ10.32_CPLL}	Sinusoidal jitter (CPLL) ⁽³⁾	10.32 Gb/s	0.30	–	–	UI	
J _{T_SJ9.953_QPLL}	Sinusoidal jitter (QPLL) ⁽³⁾	9.953 Gb/s	0.30	–	–	UI	
J _{T_SJ9.953_CPLL}	Sinusoidal jitter (CPLL) ⁽³⁾	9.953 Gb/s	0.30	–	–	UI	
J _{T_SJ8.0}	Sinusoidal jitter (CPLL) ⁽³⁾	8.0 Gb/s	0.42	–	–	UI	
J _{T_SJ6.6}	Sinusoidal jitter (CPLL) ⁽³⁾	6.6 Gb/s	0.44	–	–	UI	
J _{T_SJ5.0}	Sinusoidal jitter (CPLL) ⁽³⁾	5.0 Gb/s	0.44	–	–	UI	
J _{T_SJ4.25}	Sinusoidal jitter (CPLL) ⁽³⁾	4.25 Gb/s	0.44	–	–	UI	
J _{T_SJ3.2}	Sinusoidal jitter (CPLL) ⁽³⁾	3.2 Gb/s ⁽⁴⁾	0.45	–	–	UI	
J _{T_SJ2.5}	Sinusoidal jitter (CPLL) ⁽³⁾	2.5 Gb/s ⁽⁵⁾	0.30	–	–	UI	
J _{T_SJ1.25}	Sinusoidal jitter (CPLL) ⁽³⁾	1.25 Gb/s ⁽⁶⁾	0.30	–	–	UI	
J _{T_SJ500}	Sinusoidal jitter (CPLL) ⁽³⁾	500 Mb/s ⁽⁷⁾	0.30	–	–	UI	
SJ Jitter Tolerance with Stressed Eye ⁽²⁾							
J _{T_TJSE3.2}	Total jitter with stressed eye ⁽⁸⁾	3.2 Gb/s	0.70	–	–	UI	
J _{T_TJSE6.6}		6.6 Gb/s	0.70	–	–	UI	
J _{T_SJSE3.2}	Sinusoidal jitter with stressed eye ⁽⁸⁾	3.2 Gb/s	0.10	–	–	UI	
J _{T_SJSE6.6}		6.6 Gb/s	0.10	–	–	UI	

Notes:

- Using RXOUT_DIV = 1, 2, and 4.
- All jitter values are based on a bit error ratio of 10^{–12}.
- The frequency of the injected sinusoidal jitter is 80 MHz.
- CPLL frequency at 3.2 GHz and RXOUT_DIV = 2.
- CPLL frequency at 2.5 GHz and RXOUT_DIV = 2.
- CPLL frequency at 2.5 GHz and RXOUT_DIV = 4.
- CPLL frequency at 2.0 GHz and RXOUT_DIV = 8.
- Composite jitter with RX equalizer enabled. DFE disabled.

Integrated Interface Block for 100G Ethernet MAC and PCS

More information and documentation on solutions using the integrated 100 Gb/s Ethernet block can be found at [UltraScale Integrated 100G Ethernet MAC/PCS](#). The *UltraScale Architecture and Product Overview* (DS890) lists how many blocks are in each Virtex UltraScale+ FPGA.

Table 56: Maximum Performance for 100G Ethernet Designs

Symbol	Description	Speed Grade and V _{CCINT} Operating Voltages				Units
		0.90V	0.85V		0.72V	
		-3	-2 ⁽¹⁾	-1	-2	
F _{TX_CLK}	Transmit clock	390.625	390.625	322.223	322.223	MHz
F _{RX_CLK}	Receive clock	390.625	390.625	322.223	322.223	MHz
F _{RX_SERDES_CLK}	Receive serializer/deserializer clock	390.625	390.625	322.223	322.223	MHz
F _{DRP_CLK}	Dynamic reconfiguration port clock	250.00	250.00	250.00	250.00	MHz

Notes:

1. The maximum clock frequency of 390.625 MHz only applies to the CAUI-10 interface. The maximum clock frequency for the CAUI-4 interface is 322.223 MHz.

Integrated Interface Block for PCI Express Designs

More information and documentation on solutions for PCI Express designs can be found at [PCI Express](#). The *UltraScale Architecture and Product Overview* (DS890) lists how many blocks are in each Virtex UltraScale+ FPGA.

Table 57: Maximum Performance for PCI Express Designs⁽¹⁾⁽²⁾

Symbol	Description	Speed Grade and V _{CCINT} Operating Voltages				Units
		0.90V	0.85V		0.72V	
		-3	-2	-1	-2	
F _{PIPECLK}	Pipe clock maximum frequency.	250.00	250.00	250.00	250.00	MHz
F _{CORECLK}	Core clock maximum frequency.	500.00	500.00	500.00	250.00	MHz
F _{DRPCLK}	DRP clock maximum frequency.	250.00	250.00	250.00	250.00	MHz
F _{MCAPCLK}	MCAP clock maximum frequency.	125.00	125.00	125.00	125.00	MHz

Notes:

1. PCI Express Gen4 operation is supported for x1, x2, x4, and x8 widths.
2. PCI Express Gen4 operation is supported in -3E, -2E, and -2I speed grades.

System Monitor Specifications

Table 58: System Monitor Specifications

Parameter	Symbol	Comments/Conditions	Min	Typ	Max	Units
$V_{CCADC} = 1.8V \pm 3\%$, $V_{REFP} = 1.25V$, $V_{REFN} = 0V$, $ADCCLK = 5.2\text{ MHz}$, $T_j = -40^{\circ}C$ to $100^{\circ}C$, typical values at $T_j = 40^{\circ}C$						
ADC Accuracy ⁽¹⁾						
Resolution			10	–	–	Bits
Integral nonlinearity ⁽²⁾	INL		–	–	± 1.5	LSBs
Differential nonlinearity	DNL	No missing codes, guaranteed monotonic	–	–	± 1	LSBs
Offset error		Offset calibration enabled	–	–	± 2	LSBs
Gain error			–	–	± 0.4	%
Sample rate			–	–	0.2	MS/s
RMS code noise		External 1.25V reference	–	–	1	LSBs
		On-chip reference	–	1	–	LSBs
ADC Accuracy at Extended Temperatures						
Resolution		$T_j = -55^{\circ}C$ to $125^{\circ}C$	10	–	–	Bits
Integral nonlinearity	INL	$T_j = -55^{\circ}C$ to $125^{\circ}C$	–	–	± 1.5	LSBs
Differential nonlinearity	DNL	No missing codes, guaranteed monotonic $T_j = -55^{\circ}C$ to $125^{\circ}C$	–	–	± 1	
Analog Inputs ⁽²⁾						
ADC input ranges		Unipolar operation	0	–	1	V
		Bipolar operation	–0.5	–	+0.5	V
		Unipolar common mode range (FS input)	0	–	+0.5	V
		Bipolar common mode range (FS input)	+0.5	–	+0.6	V
Maximum external channel input ranges		Adjacent channels set within these ranges should not corrupt measurements on adjacent channels	–0.1	–	V_{CCADC}	V
On-Chip Sensor Accuracy						
Temperature sensor error ⁽¹⁾⁽³⁾		$T_j = -55^{\circ}C$ to $125^{\circ}C$ (with external REF)	–	–	± 3	$^{\circ}C$
		$T_j = -55^{\circ}C$ to $110^{\circ}C$ (with internal REF)	–	–	± 3.5	$^{\circ}C$
		$T_j = 110^{\circ}C$ to $125^{\circ}C$ (with internal REF)	–	–	± 5	$^{\circ}C$